



Radiation-Susceptibility of Display Technologies for Manned Missions

2REDPANDAS

Landen Ryder, GSFC

Acronyms



- 2REDPANDAS: Radiation tolerant and Reliable Electronic Displays: a Preliminary Assessment Necessary for Deep-spaceflight ApplicationS
- AES: Advanced Exploration Systems
- COTS: Commercial Off The Shelf
- DCM: Display and Control Module
- EMU: Extravehicular Mobility Units
- GSFC: Goddard Space Flight Center
- HEO: Human Exploration and Operations
- IC: Integrated Circuit
- JSC: Johnson Space Center
- LARC: LAngley Research Center
- LCD: Liquid Crystal Display
- LED: Light Emitting Diode
- LET: Linear Energy Transfer
- NEPP: NASA Electronic Parts and Packaging
- OLED: Organic Light Emitting Diode
- RWS: Robotic WorkStation
- SBIR: Small Business Innovation Research
- SEE: Single Event Effects
- SEFI: Single Event Functional Interrupt
- SEL: Single Event Latch-Up
- STTR: Small business Technology Transfer
- TFT: Thin Film Transistor
- RAM: Random Access Memory

Displays in Space



- **International Space Station**

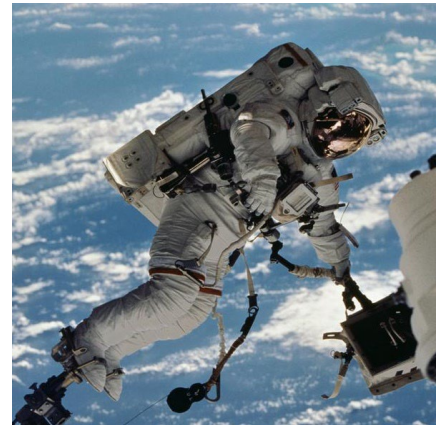
- 100+ COTS Laptops
- Robotic Workstation (RWS)
- Medical equipment, wearables

- **Extravehicular Mobility Unit (EMU)**

- Display & Control Module (DCM)
 - 12-character LCD provides basic parametric and fault information

- **SpaceX Crew Dragon**

- 3 Touchscreen Display Units
- Display Button Panels
- Armrest Seat Panels
- COTS Crew Tablets



Humans
Love
Screen
Time!





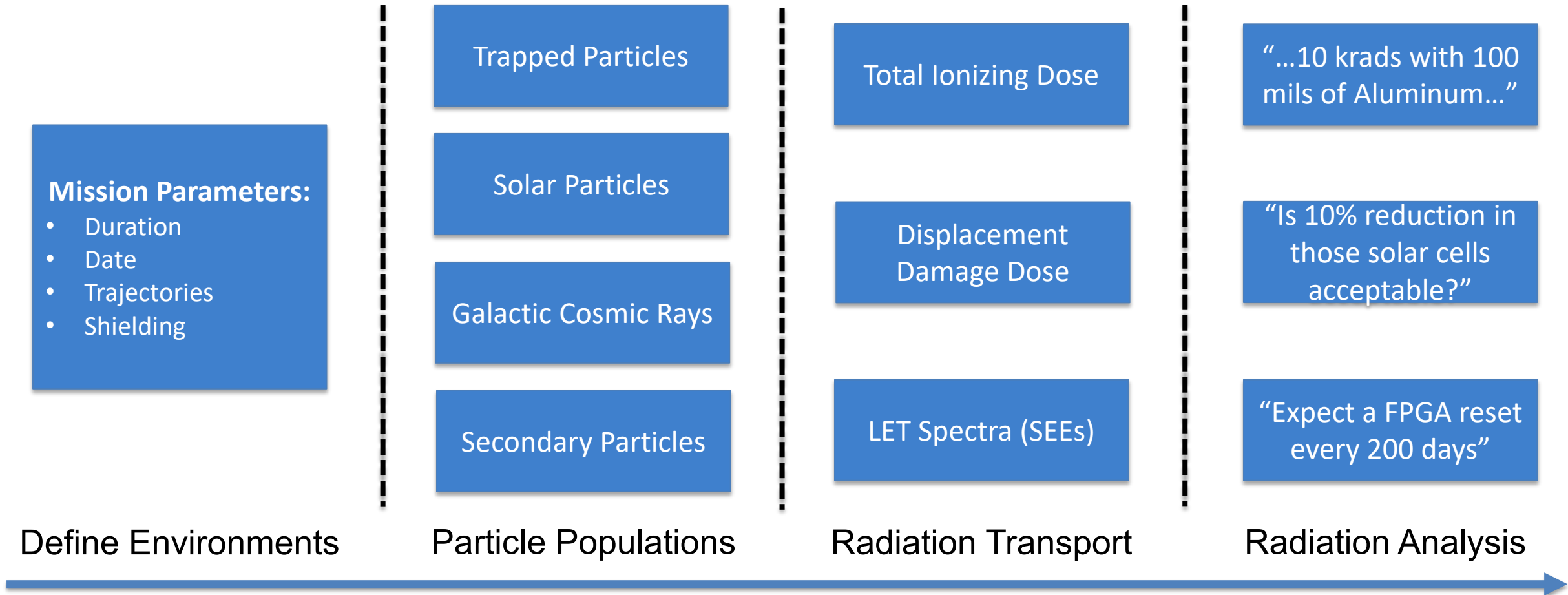
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Available: <https://www.toyota-europe.com/world-of-toyota/articles-news-events/2019/toyota-jaxa>

- **2021 Polaris Project – two-year AES-HEO funded project managed by early careers**
 - Address the knowledge gap for radiation-tolerant displays for future manned missions
- **Cross-Center Collaboration:**
 - JSC: **Justin Bautista, Tyler Garrett**, Brian Schwing, Razvan Gaza
 - GSFC: **Landen Ryder**, Ed Wyrwas, Michael Campola, Jonny Pellish, Wesley Powell
 - LARC: **Sharon Xu**, Lisa Simonsen

Radiation Environment Modelling



- **Radiation environment modelling bridges measurements and mission environments**
 - Single experimental datasets can be generalized to many mission environments through modelling

Commercial Off the Shelf Displays



- **Variety of Commercial Pixel Technologies**

- Light Emitting Diodes (LED)
- Liquid Crystal Displays w/ LED backlight (LCD)
- Electronic Ink (reflective or LED backlight)
- Organic LEDs

- **Common Key Performance Indicators:**

- Brightness, Contrast Ratio, Color Mixing
- Pixel Density, Viewing Angle, Uniformity
- Size, Weight, Rigidity, Thermal Stability
- Refresh Rate, Power Draw, Resolution

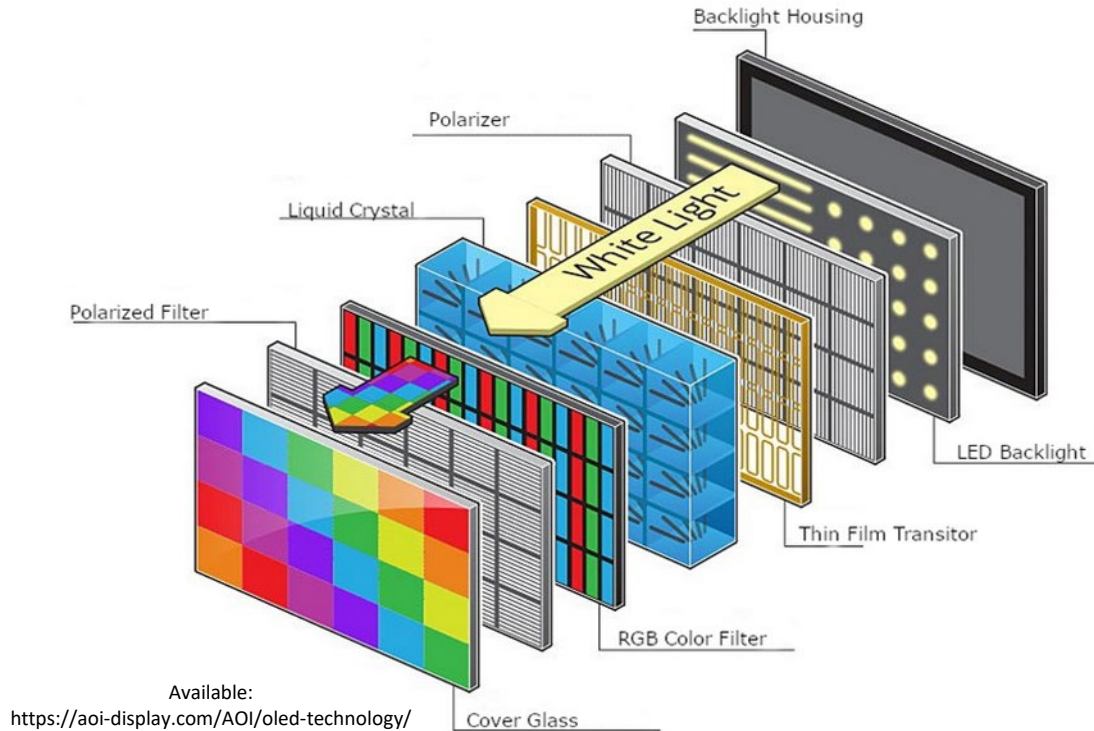
- **Pixel technologies for display-integrated products vary based on performance/price**

- LEDs and LCD for cost effectiveness
- OLED for maximum performance

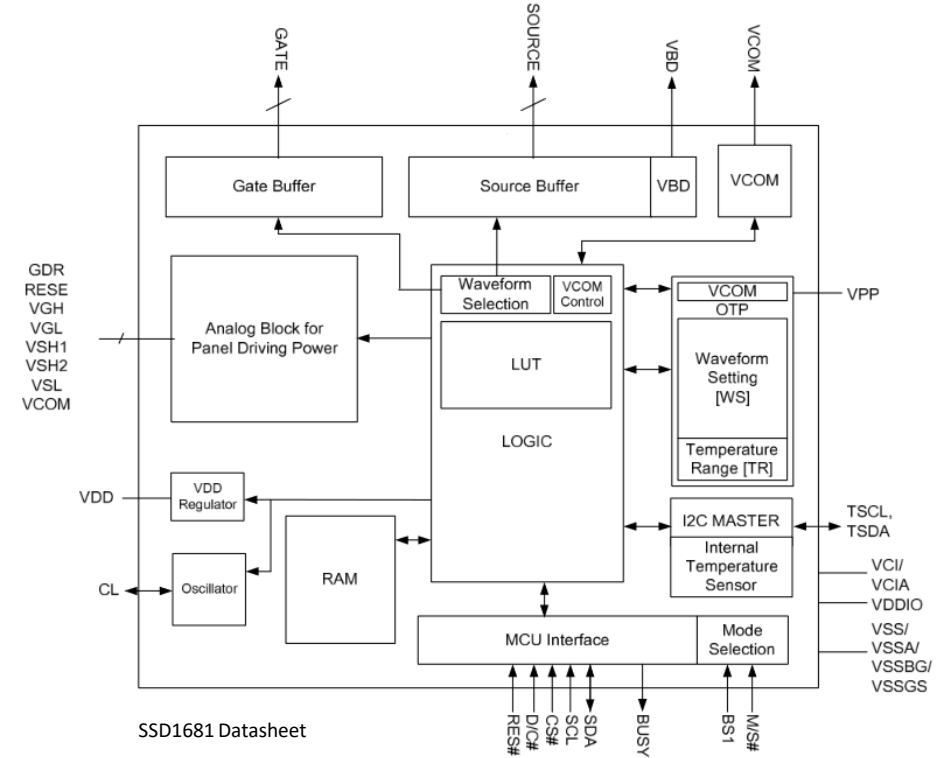


Breaking Down Displays

Screens



Support Circuitry

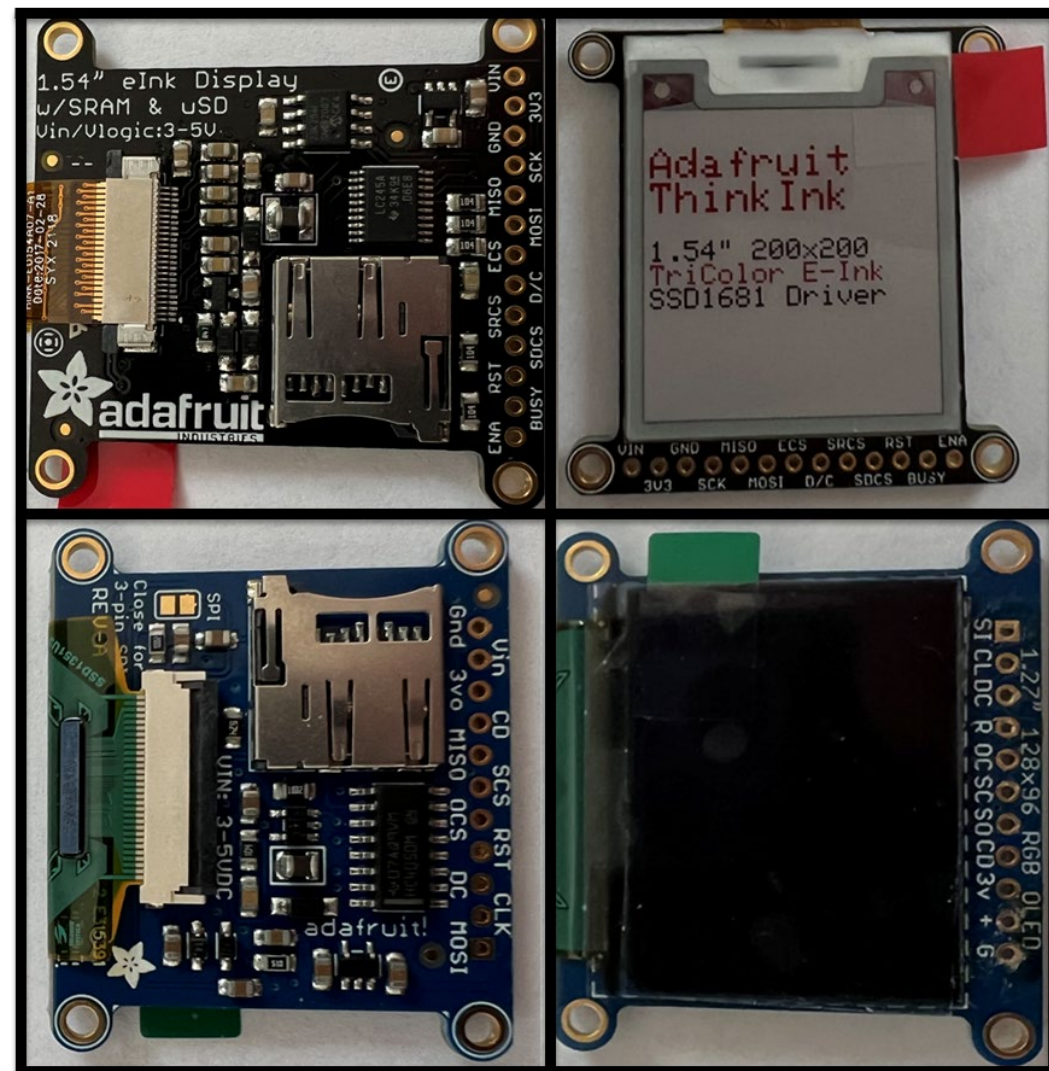


- Notional display pixel screen material stack consists of structural support, polarizers, passivation layers, thin-film transistors (TFT), light emission/modulation layers
- Support electronics are packaged with displays to manage input signal, drive the pixels
 - Row/column drivers, timing circuits, power management, RAM, microcontrollers, transceivers, etc.

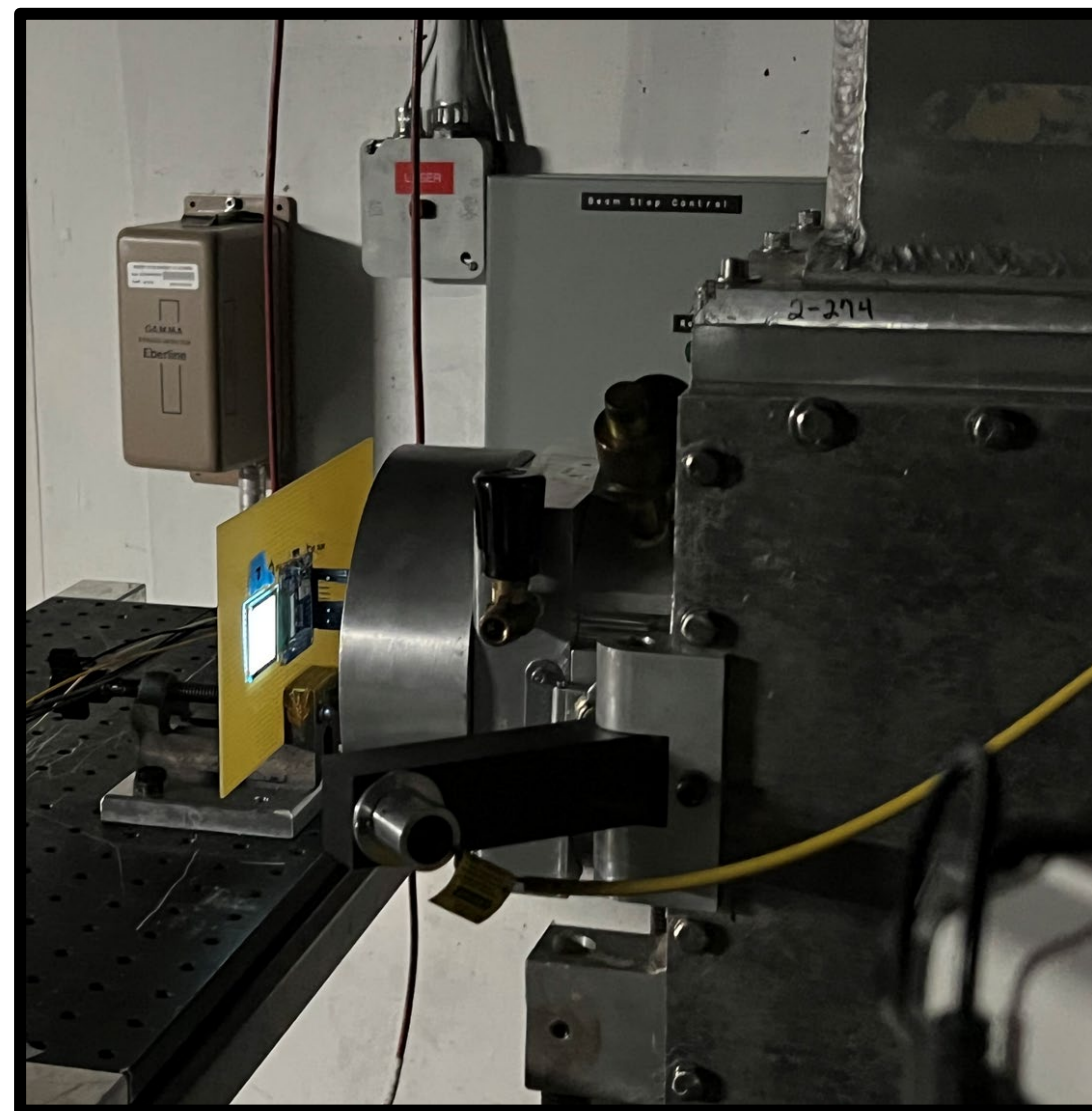
Developing Display Test Capabilities

- **Testing and Characterization Techniques – Idealism vs. Pragmatism**
 - Industry standard performance metrics often necessitate complex, time-intensive characterization
 - On-site testing requires adaptable, transportable, efficient characterization equipment and techniques
- **Utilize existing NEPP capabilities/expertise, procure additional equipment when required**
 - 3D printing for prototyping test harnesses for irradiation and characterization (e.g., light boxes)
 - Industry experience with displays for reconfiguring display packaging, testing pitfalls
 - Procuring handheld optical meters to assess spectral information, brightness for test campaigns
- **Testing displays requires techniques not associated with typical EEE parts**
 - Post-processing images with ImageJ – open source, scriptable software for analyzing image files
 - Develop an approach for end-user SEE testing – single pixels, frame drops, SEFIs, Latch-up

- LCDs, LEDs, OLED, and E-Ink displays units are being procured for irradiation
- Display candidates for testing
 - Commercially available, part-to-part variation
 - Small footprint to optimize beam overlap
 - Modifiable packaging for radiation testing
 - Compatibility with common microcontrollers
 - Public facing software libraries for prototyping
 - No additional thermal mitigation required
- Results will be “generalizable” to larger displays
 - Pixel degradation will be normalized, per pixel
 - Duplicate ICs often required for larger displays, susceptibility will scale with number of ICs



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Displacement Damage/Total Ionizing Dose Measurements

- **64 MeV proton irradiation at UC Davis Crocker National Lab's 76" Cyclotron**
 - Preliminary test in May, Full scale test in September
- **Units will be configured to irradiate display screens, avoid support electronics**
 - Facility provide apertures used confine exposure region to a region of the screen, cameras to monitor displays for irregular behavior during irradiation
 - Displays will be driven with test pattern to capture impact of the on/off state of the pixel
 - Additional test routines to manipulate/stress displays without resetting displays
- **Irradiation is conducted in discrete steps with characterization between each step**
 - Handheld optical meters capture display brightness, optical spectrum for post-processing
 - Current draw for a benchmark operation for increased power consumption
 - Post-anneal measurements for estimation of permanent degradation

Single Event Effects Measurements

- **Heavy ion testing is targeting in air at Lawrence Berkley National Lab's 88" Cyclotron**
- **Units will be configured to irradiate support electronics, shield off-board controllers**
 - Test setups include remote power cycling to clear persistent error states between runs
- **Power supplies/cameras will be monitored to identify error signatures**
 - Pixel/Line/Screen dropouts will be captured via camera monitoring
 - Current draw can be used differentiate errors (Functional Interrupts vs. Latch Up)
- **Tabulation of error counts with particle fluence used to produce error cross-sections**
 - Cross-section curves can be used to estimate error rates (e.g. power cycle every five minutes)
 - Identify sensitive ICs that span display technologies for potential radiation-hardened substitutes
 - Investigate potential trade spaces for display operation (e.g. error rate vs. frame rate)

- **Next generation manned mission will require radiation-tolerant displays to ensure consistent, accurate human interfacing for the duration of long-term missions**
- **Develop the body-of-knowledge, testing capabilities for future manned mission needs**
 - Broad characterization of technologies sensitivities – “Should we use LCDs or OLEDs?”
 - Impact of design features on radiation tolerance – “Edge-coupled or back-lite LCD screens?”
 - Refine techniques for radiation testing of displays – “We have already bought these displays, so...”
- **Engage with industry via existing partnerships, SBIR/STTR proposals, conferences**
 - Identification of common susceptibilities in the support hardware chain for potential hardening
 - Understand manufacturer’s fabrication, integration processes and availability of modification
- **Development of NASA Early Careers via mentorship, cross-center collaboration**